

Checking Safety Properties of Sequential Programs via Static Analysis

Thomas Ball
Microsoft Research, Redmond, USA

At Microsoft, we now regularly apply a new generation of static analysis tools that can automatically identify serious defects in programs. These tools examine millions of lines of code every day, long before the software is released for general use. With these tools, we catch more defects earlier in the software process, enabling Microsoft to deliver more reliable systems. A number of these tools have been released for general use through Microsoft's Visual Studio integrated development environment as well as freely available development kits. In my lectures I will address the question: "How does one design and implement a static analysis tool chain to help people effectively address a software reliability problem?" In particular, I will identify a set of basic techniques that have proven very useful in constructing static analysis tools and have shown their worth through numerous applications. Experience with these techniques suggests we are approaching an exciting time when more people can contribute to the design and implementation of static analysis tools.

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